

Docket No. 243203US2RD

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



IN RE APPLICATION OF: Hideki SATAKE

SERIAL NO: 10/670,279

GAU: 2814

FILED: September 26, 2003

EXAMINER: PHAM, LONG

FOR: SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE SAME

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

The applicant(s) wish to make of record the references cited in the attached Supplementary European Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

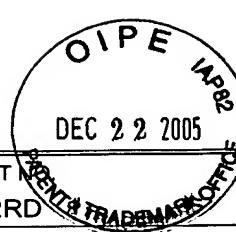
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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243203US2RD	SERIAL NO. 10/670,279	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Hideki SATAKE				
		FILING DATE September 26, 2003		GROUP 2814		
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	AA	6,225,151	5/1/2001	GARDNER et al.		
	AB	5,827,774	10/27/1998	KITAJIMA		
	AC	6,300,664	10/9/2001	KUROI et al.		
	AD	6,288,433	9/11/2001	AKRAM et al.		
	AE	5,885,884	3/23/1999	JAN et al.		
	AF	6,242,356	6/5/2001	JANG et al.		
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
	AM					
	AN					
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
	AO	EP 0 350 845	1/17/1990	EUROPE	<input checked="" type="checkbox"/> YES	<input type="checkbox"/> NO
	AP	EP 0 706 204	4/10/1996	EUROPE	<input checked="" type="checkbox"/> YES	<input type="checkbox"/> NO
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)						
	AW	YASUOKA, A. et al., "THE EFFECTS ON METAL OXIDE SEMICONDUCTOR FIELD EFFECT TRANSISTOR PROPERTIES OF NITROGEN IMPLANTATION INTO P+ POLYSILICON GATE", Japanese Journal of Applied Physics, Vol. 36, No. 2, February 1997, pgs. 617-622, XP-000735532				
	AX	HSING-HUANG TSENG, "FLUORINE DIFFUSION ON A POLYSILICON GRAIN BOUNDARY NETWORK IN RELATION TO BORON PENETRATION FROM P+ GATES", IEEE Electron Device Letters, Vol. 13, No. 1, January 1992, pgs. 14-16, XP 000244049				
	AY					
	AZ				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner					Date Considered	
<p>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>						

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